


<b>Search Notes</b> 	<b>Application/Control No.</b> 10773640	<b>Applicant(s)/Patent Under Reexamination</b> CHEN ET AL.
	<b>Examiner</b> PHUC TRAN	<b>Art Unit</b> 2471

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East updated search and text search for interference	1/15/2010	pt

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	see history printout	1/15/2010	pt

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